

IFN5196, IFN5197, IFN5198, IFN5199

N-Channel Matched Dual Silicon Junction Field-Effect Transistor

- Improved Replacement for the 2N5196, 2N5197, 2N5198, 2N5199
- Differential Inputs

Absolute maximum ratings at $T_A = 25^\circ\text{C}$

Reverse Gate Source & Gate Drain Voltage	-50V
Continuous Forward Gate Current	50 mA
Continuous Device Power Dissipation	250 mW
Power Derating	2.6 mW/ $^\circ\text{C}$
Operating Temperature Range	-55 $^\circ\text{C}$ to +125 $^\circ\text{C}$
Storage Temperature Range	-65 $^\circ\text{C}$ to +150 $^\circ\text{C}$

At 25 $^\circ\text{C}$ free air temperature

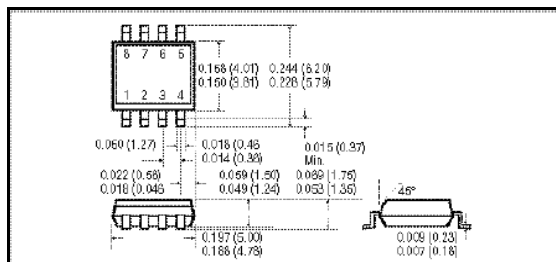
Static Electrical Characteristics

IFN5196, IFN5197, IFN5198, IFN5199						Process NJ16	
		Min	Typ	Max	Unit	Test Conditions	
Gate Source Breakdown Voltage	$V_{(BR)GSS}$	-50			V	$I_G = -1 \mu\text{A}$, $V_{DS} = 0 \text{ V}$	
Gate Reverse Current	I_{GSS}			-25 -50	pA nA	$V_{GS} = -30 \text{ V}$, $V_{DS} = 0 \text{ V}$	150 $^\circ\text{C}$
Gate Current	I_G			-50 -15	pA nA	$V_{DG} = 10 \text{ V}$, $I_D = -200 \mu\text{A}$	125 $^\circ\text{C}$
Gate Source Cutoff Voltage	$V_{GS(OFF)}$	-0.7		-4	V	$V_{DS} = 20 \text{ V}$, $I_D = 1 \text{ nA}$	
Drain Saturation Current (pulsed)	I_{DSS}	0.7		7	mA	$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$	
Gate Source Voltage	V_{GS}	-0.2		-3.8	V	$V_{DG} = 20 \text{ V}$, $I_D = -200 \mu\text{A}$	

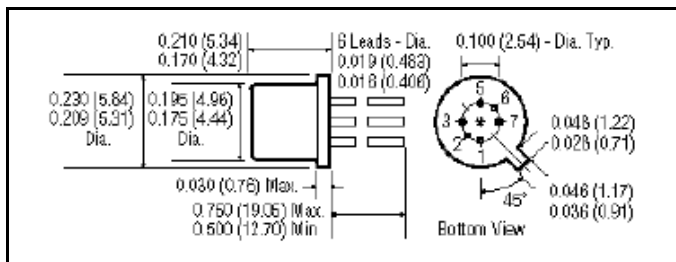
Dynamic Electrical Characteristics

Common-Source Forward Transconductance	g_{fs}	1		4	mS	$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$	$f = 1 \text{ kHz}$
Common-Source Output Conductance	g_{os}			50	μS	$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$	$f = 1 \text{ kHz}$
Common-Source Input Capacitance	C_{iss}			6	pF	$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$	$f = 1 \text{ MHz}$
Common-Source Reverse Transfer Capacitance	C_{rss}			2	pF	$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$	$f = 1 \text{ MHz}$
Noise Factor $R_G = 10 \text{ M}\Omega$	NF			0.5	dB	$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$	$f = 100 \text{ Hz}$
Equivalent Short Circuit Input Noise Voltage	$\sim e_N$			20	nV/ $\sqrt{\text{Hz}}$	$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$	$f = 1 \text{ kHz}$

		IFN5196		IFN5197		IFN5198		IFN5199		Units	Test Conditions
		Min	Max	Min	Max	Min	Max	Min	Max		
Differential Gate-Source Voltage	$ V_{GS1} - V_{GS2} $		5		5		10		15	mV	$V_{DG} = 20 \text{ V}$, $I_D = -200 \mu\text{A}$
Differential Gate Source Voltage with Temperature ¹	$\frac{\Delta V_{GS1} - V_{GS2} }{\Delta T}$		5		10		20		40	$\mu\text{V}/^\circ\text{C}$	$V_{DG} = 20 \text{ V}$, $I_D = -200 \mu\text{A}$
Differential Gate Current @125 $^\circ$	$ I_{G1} - I_{G2} $		5		5		5		5	nA	$V_{DG} = 20 \text{ V}$, $I_D = -200 \mu\text{A}$
Saturation Drain Current Ratio	$\frac{I_{DSS1}}{I_{DSS2}}$	0.95	1	0.95	1	0.95	1	0.95	1		$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$
Transconductance Ratio @ $f = 1 \text{ kHz}$	$\frac{g_{fs1}}{g_{fs2}}$	0.97	1	0.97	1	0.95	1	0.95	1		$V_{DG} = 20 \text{ V}$, $I_D = -200 \mu\text{A}$
Differential Output Conductance @ $f = 1 \text{ kHz}$	$ g_{os1} - g_{os2} $		1		1		1		1	μS	$V_{DG} = 20 \text{ V}$, $I_D = -200 \mu\text{A}$



SOIC-8 Package Pin Configuration
SMP5196, SMP5197, 1-G1, 2-D1, 3-S1, 4-G2,
SMP5198, SMP5199 5-G2, 6-D2, 7-S2, 8-G1



TO-71: Pin Configuration
IFN5196, IFN5197, 1-S1, 2-D1, 3-G1,
IFN5198, IFN5199 4-S2, 5-D2, 6-G2

Note 1: $T = -55^\circ\text{C}$, 25°C , 125°C

Note 2: Dimensions in Inches (mm)



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